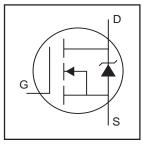
PD - 95062A

IRLR2705PbFIRLU2705PbF

HEXFET® Power MOSFET



- Logic-Level Gate Drive
- Ultra Low On-Resistance
- Surface Mount (IRLR2705)
- Straight Lead (IRLU2705)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

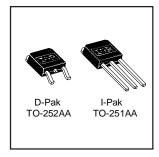


$V_{DSS} = 55V$ $R_{DS(on)} = 0.040\Omega$ $I_{D} = 28A$

Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The D-PAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



Absolute Maximum Ratings

	<u> </u>		
	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	28	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	20	A
I _{DM}	Pulsed Drain Current ①	110	
P _D @T _C = 25°C	Power Dissipation	68	W
	Linear Derating Factor	0.45	W/°C
V_{GS}	Gate-to-Source Voltage	± 16	V
E _{AS}	Single Pulse Avalanche Energy®	110	mJ
I _{AR}	Avalanche Current ①	16	A
E _{AR}	Repetitive Avalanche Energy①	6.8	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		2.2	
$R_{\theta JA}$	Case-to-Ambient (PCB mount)**		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

^{**} When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994



Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.065		V/°C	Reference to 25°C, I _D = 1mA
				0.040		V _{GS} = 10V, I _D = 17A ④
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.051	W	V _{GS} = 5.0V, I _D = 17A ⊕
				0.065		V _{GS} = 4.0V, I _D = 14A ⊕
V _{GS(th)}	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
9 _{fs}	Forward Transconductance	11			S	V _{DS} = 25V, I _D = 16A⑦
1	Drain-to-Source Leakage Current			25	μA	$V_{DS} = 55V, V_{GS} = 0V$
I _{DSS}	Dialii-to-Source Leakage Current			250	μΑ	V _{DS} = 44V, V _{GS} = 0V, T _J = 150°C
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 16V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	IIA	V _{GS} = -16V
Qg	Total Gate Charge			25		I _D = 16A
Q _{gs}	Gate-to-Source Charge			5.2	nC	$V_{DS} = 44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			14		V _{GS} = 5.0V, See Fig. 6 and 13 ⊕ ⑦
t _{d(on)}	Turn-On Delay Time		8.9			V _{DD} = 28V
t _r	Rise Time		100		ns	$I_D = 16A$
t _{d(off)}	Turn-Off Delay Time		21		115	$R_G = 6.5\Omega, V_{GS} = 5.0V$
t _f	FallTime		29			$R_D = 1.8\Omega$, See Fig. 10 \oplus \oslash
			4.5			Between lead,
L _D	Internal Drain Inductance		4.5		– nH	6mm (0.25in.)
	Internal Course Industry					from package GV
L _S	Internal Source Inductance		7.5			and center of die contact®
C _{iss}	Input Capacitance		880			V _{GS} = 0V
Coss	Output Capacitance		220		pF	$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		94			$f = 1.0 \text{MHz}$, See Fig. 5 \bigcirc

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			00		MOSFET symbol
	(Body Diode)			28	A	showing the
I _{SM}	Pulsed Source Current			440		integral reverse
	(Body Diode) ①			110		p-n junction diode.
V _{SD}	Diode Forward Voltage	_		1.3	V	$T_J = 25^{\circ}C$, $I_S = 17A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		76	110	ns	$T_J = 25^{\circ}C$, $I_F = 16A$
Q _{rr}	Reverse RecoveryCharge	_	190	290	nC	di/dt = 100A/µs ④⑦
t _{on}	Forward Turn-On Time	Intr	insic tu	rn-on ti	me is ne	egligible (turn-on is dominated by L _S +L _D)

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11) \triangledown $V_{DD} = 25V$, starting $T_J = 25^{\circ}C$, $L = 610\mu H$
- $R_G = 25\Omega$, $I_{AS} = 16A$. (See Figure 12)
- $T_J \le 175^{\circ}C$
- ④ Pulse width ≤ 300 μ s; duty cycle ≤ 2%.
- ⑤ Caculated continuous current based on maximum allowable junction temperature; Package limitation current = 20A.
- 6 This is applied for I-PAK, L_S of D-PAK is measured between lead and center of die contact.
- ① Uses IRLZ34N data and test conditions.

International TOR Rectifier

IRLR/U2705PbF

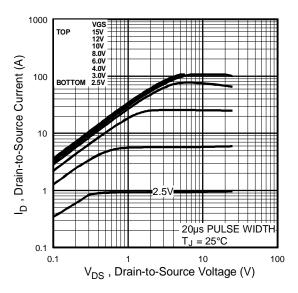


Fig 1. Typical Output Characteristics

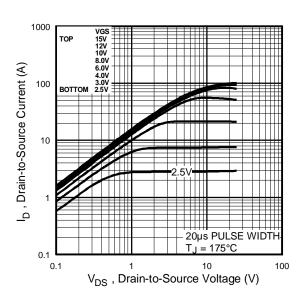


Fig 2. Typical Output Characteristics

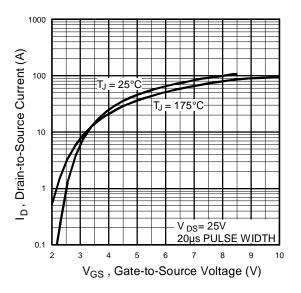


Fig 3. Typical Transfer Characteristics

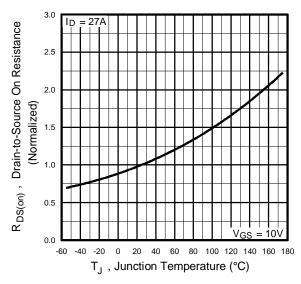


Fig 4. Normalized On-Resistance Vs. Temperature

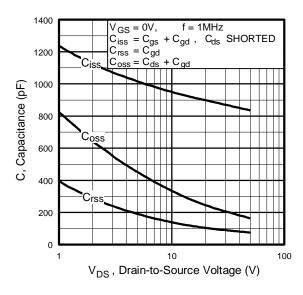


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

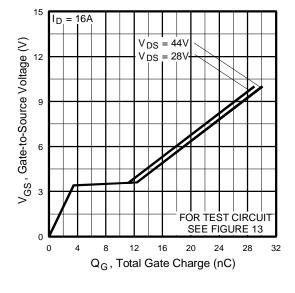


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

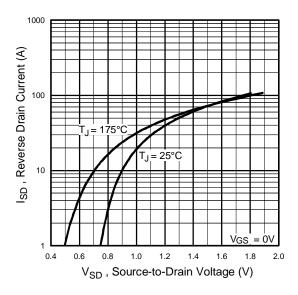


Fig 7. Typical Source-Drain Diode Forward Voltage

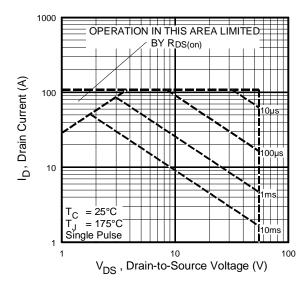


Fig 8. Maximum Safe Operating Area

International TOR Rectifier

IRLR/U2705PbF

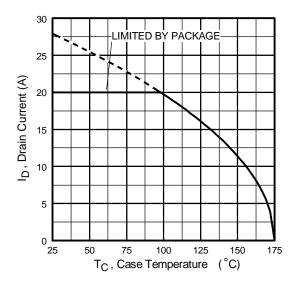


Fig 9. Maximum Drain Current Vs. Case Temperature

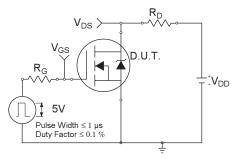


Fig 10a. Switching Time Test Circuit

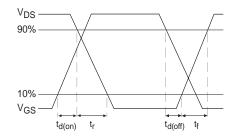


Fig 10b. Switching Time Waveforms

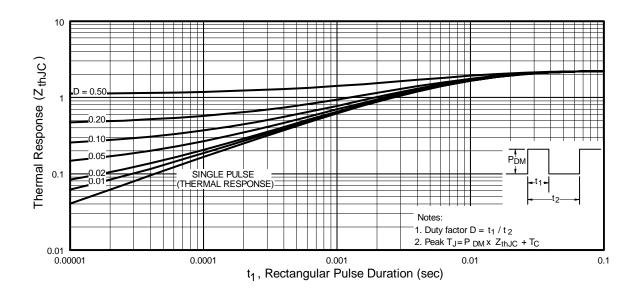


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

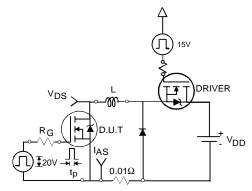


Fig 12a. Unclamped Inductive Test Circuit

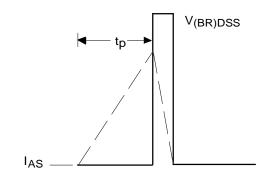


Fig 12b. Unclamped Inductive Waveforms

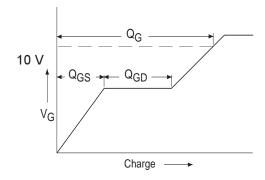


Fig 13a. Basic Gate Charge Waveform

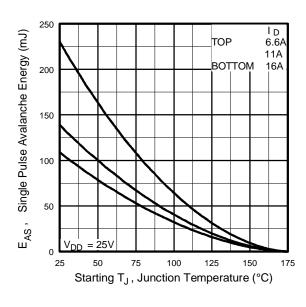


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

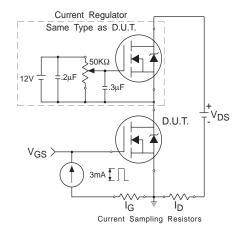
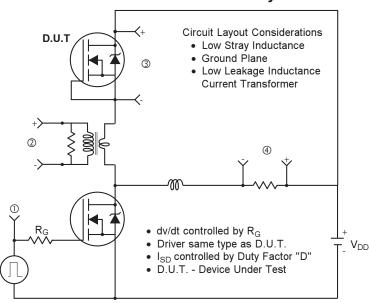
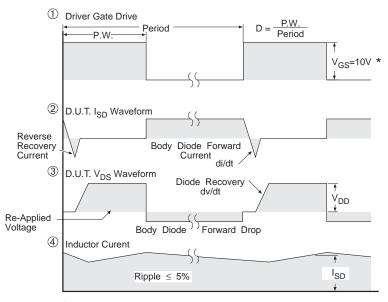


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit





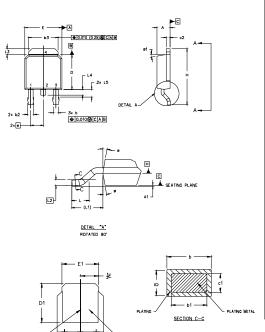
* V_{GS} = 5V for Logic Level Devices

Fig 14. For N-Channel HEXFETS



D-Pak (TO-252AA) Package Outline

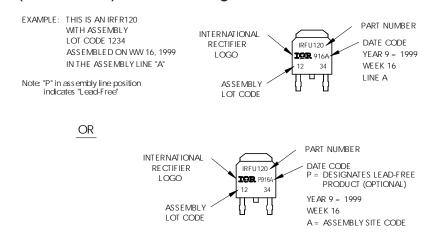
Dimensions are shown in millimeters (inches)



VIEW A-A

7,0 OUT	ILINE CO	NFORMS T	TO JEDEC	OUTLINE	TO-252AA,	
		DIMEN	SIONS			
SYMBOL	Murak	ETERS	INC	HES	i	
3111100E	WN.	MAX	Min.	MAX.	NOTES	
	2.18	2.39	086	.094		
A1	2.10	013		005		
, i	0.64	0.89	.025	.035	5	LEAD ASSIGNMENTS
ь1	0.64	0.79	.025	0.031		
b2	0.76	1,14	.030	.045		HEXFET
b3	4.95	5.46	.195	.215		
c	0.46	0.61	.018	.024	5	1 GATE
c1	0.41	0.56	.016	.022	5	2 DRAIN 3 SOURCE
c2	.046	0.89	.018	.035	5	4 DRAIN
D	5.97	6.22	235	.245	6	4. Pront
D1	5.21	-	205		4	
E	6.35	6.73	.250	.265	6	IGBTs, CoPACK
E1	4 32		.170		•	1 GATE
, L	9.40	10.41	.370	.410	1	2 COLLECTOR
."	1,40	1.78	.055	.070		3 EMITTER
i F	2.74		.108			4 COLLECTOR
ا ا يا	0.051			BSC	1	
L3	0.89	1.27	.035	.050	1	
L4		1.02		040		
L5	1.14	1,52	.045	.060	3	
	o.	10"	0.	10*		
p1	o.	15"	0.	15*		

D-Pak (TO-252AA) Part Marking Information

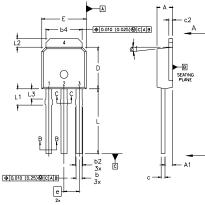


International IOR Rectifier

IRLR/U2705PbF

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



ES	:				
	DIMENCIONING	AND	TOLEDANIONIC	DED	ACLIE

NOTE

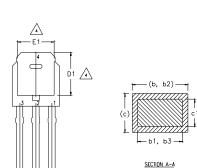
- PER ASME Y14.5 M- 1994.
- DIMENSIONING AND IOLERANCING PER ASME Y14.5 M 1994.
 DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
 DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED
 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST
 EXTREMES OF THE PLASTIC BODY.
- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1. LEAD DIMENSION UNCONTROLLED IN L3.
- DIMENSION 61, 63 APPLY TO BASE METAL ONLY. OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA, CONTROLLING DIMENSION: INCHES,

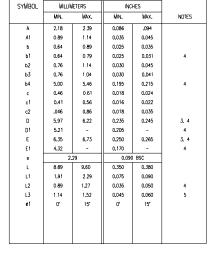
DIMENSIONS

LEAD ASSIGNMENTS

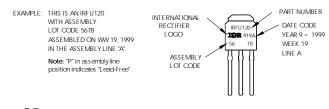
<u>HEXFET</u>					
1	GATE				
2 -	DRAIN				

KI LI
GATE
DRAIN
SOURCE
DRAIN

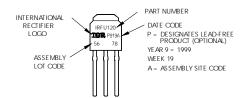




I-Pak (TO-251AA) Part Marking Information



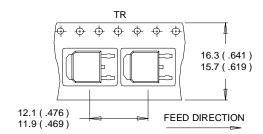


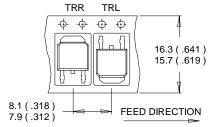


International IOR Rectifier

D-Pak (TO-252AA) Tape & Reel Information

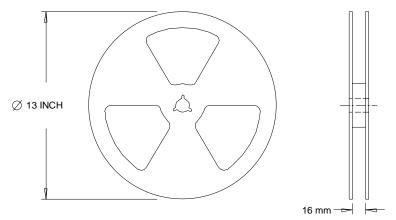
Dimensions are shown in millimeters (inches)





NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Data and specifications subject to change without notice.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information.01/05

Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

IMPORTANT NOTICE

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie").

With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (www.infineon.com).

WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may not be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.